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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

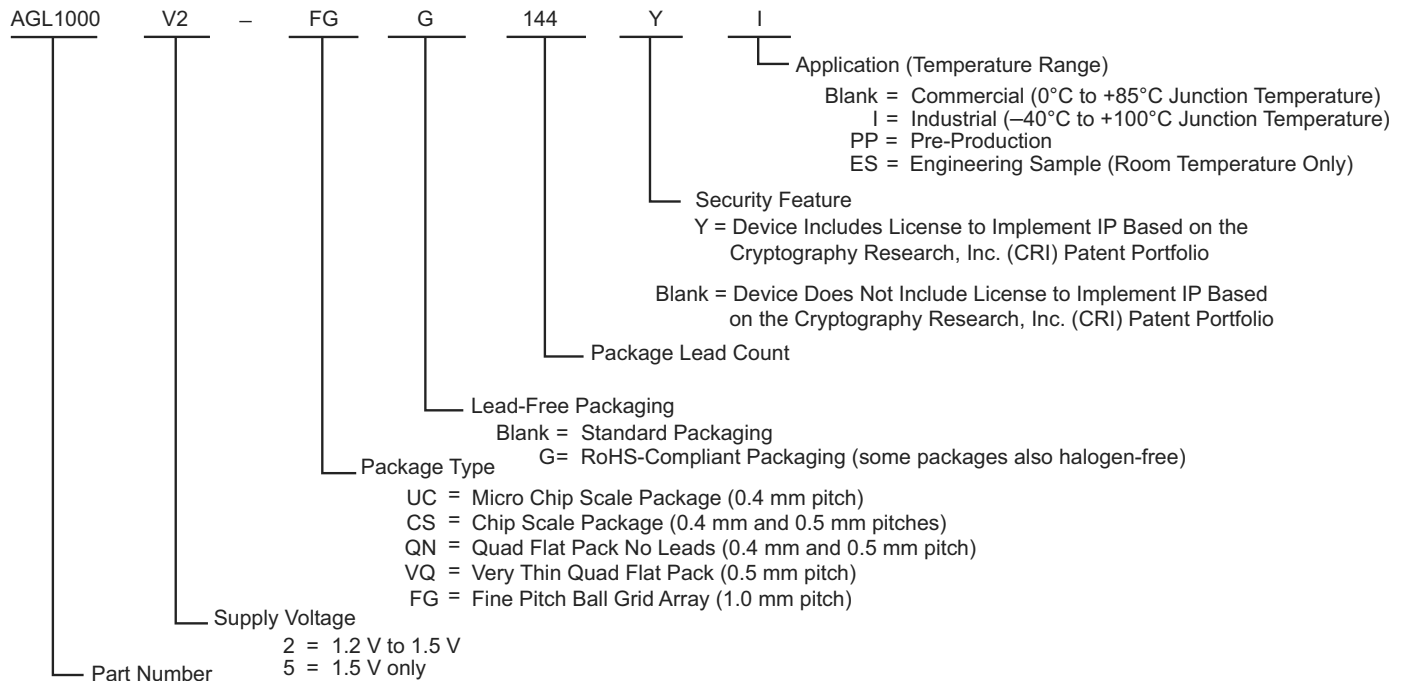
Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Active
Number of LABs/CLBs	-
Number of Logic Elements/Cells	6144
Total RAM Bits	36864
Number of I/O	143
Number of Gates	250000
Voltage - Supply	1.425V ~ 1.575V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 85°C (TA)
Package / Case	196-TFBGA, CSBGA
Supplier Device Package	196-CSP (8x8)
Purchase URL	https://www.e-xfl.com/product-detail/microchip-technology/agl250v5-csg196i

IGLOO Ordering Information



IGLOO Devices

- AGL015 = 15,000 System Gates
- AGL030 = 30,000 System Gates
- AGL060 = 60,000 System Gates
- AGL125 = 125,000 System Gates
- AGL250 = 250,000 System Gates
- AGL400 = 400,000 System Gates
- AGL600 = 600,000 System Gates
- AGL1000 = 1,000,000 System Gates

IGLOO Devices with Cortex-M1

- M1AGL250 = 250,000 System Gates
- M1AGL600 = 600,000 System Gates
- M1AGL1000 = 1,000,000 System Gates

Note: Marking Information: IGLOO V2 devices do not have V2 marking, but IGLOO V5 devices are marked accordingly.

**Table 2-17 • Summary of I/O Output Buffer Power (per pin) – Default I/O Software Settings¹
Applicable to Standard Plus I/O Banks**

	C_{LOAD} (pF)	VCCI (V)	Static Power PDC7 (mW) ²	Dynamic Power PAC10 (μ W/MHz) ³
Single-Ended				
3.3 V LVTTTL / 3.3 V LVCMOS	5	3.3	–	122.16
3.3 V LVCMOS Wide Range ⁴	5	3.3	–	122.16
2.5 V LVCMOS	5	2.5	–	68.37
1.8 V LVCMOS	5	1.8	–	34.53
1.5 V LVCMOS (JESD8-11)	5	1.5	–	23.66
1.2 V LVCMOS ⁵	5	1.2	–	14.90
1.2 V LVCMOS Wide Range ⁵	5	1.2	–	14.90
3.3 V PCI	10	3.3	–	181.06
3.3 V PCI-X	10	3.3	–	181.06

Notes:

1. Dynamic power consumption is given for standard load and software default drive strength and output slew.
2. P_{DC7} is the static power (where applicable) measured on VCCI.
3. P_{AC10} is the total dynamic power measured on VCCI.
4. All LVCMOS 3.3 V software macros support LVCMOS 3.3 V wide range as specified in the JESD-8B specification.
5. Applicable for IGLOO V2 devices only.

**Table 2-18 • Summary of I/O Output Buffer Power (per pin) – Default I/O Software Settings¹
Applicable to Standard I/O Banks**

	C_{LOAD} (pF)	VCCI (V)	Static Power PDC7 (mW) ²	Dynamic Power PAC10 (μ W/MHz) ³
Single-Ended				
3.3 V LVTTTL / 3.3 V LVCMOS	5	3.3	–	104.38
3.3 V LVCMOS Wide Range ⁴	5	3.3	–	104.38
2.5 V LVCMOS	5	2.5	–	59.86
1.8 V LVCMOS	5	1.8	–	31.26
1.5 V LVCMOS (JESD8-11)	5	1.5	–	21.96
1.2 V LVCMOS ⁵	5	1.2	–	13.49
1.2 V LVCMOS Wide Range ⁵	5	1.2	–	13.49

Notes:

1. Dynamic power consumption is given for standard load and software default drive strength and output slew.
2. P_{DC7} is the static power (where applicable) measured on VCCI.
3. P_{AC10} is the total dynamic power measured on VCCI.
4. All LVCMOS 3.3 V software macros support LVCMOS 3.3 V wide range as specified in the JESD-8B specification.
5. Applicable for IGLOO V2 devices only.

Table 2-36 • Summary of I/O Timing Characteristics—Software Default Settings, Std. Speed Grade, Commercial-Case Conditions: $T_J = 70^\circ\text{C}$, Worst-Case $V_{CC} = 1.14\text{ V}$, Worst-Case V_{CCI} (per standard) Applicable to Standard I/O Banks

I/O Standard	Drive Strength	Equivalent Software Default Drive Strength Option ¹ (mA)	Slew Rate	Capacitive Load (pF)	External Resistor (Ω)	t_{DOUT} (ns)	t_{DP} (ns)	t_{DIN} (ns)	t_{PY} (ns)	t_{EOUT} (ns)	t_{ZL} (ns)	t_{ZH} (ns)	t_{LZ} (ns)	t_{HZ} (ns)	Units
3.3 V LVTTTL / 3.3 V LVC MOS	8 mA	8	High	5	–	1.55	2.38	0.26	0.94	1.10	2.41	1.92	2.40	2.96	ns
3.3 V LVC MOS Wide Range ³	100 μA	8	High	5	–	1.55	3.33	0.26	1.29	1.10	3.33	2.62	3.34	4.07	ns
2.5 V LVC MOS	8 mA	8	High	5	–	1.55	2.39	0.26	1.15	1.10	2.42	2.05	2.38	2.80	ns
1.8 V LVC MOS	4 mA	4	High	5	–	1.55	2.60	0.26	1.08	1.10	2.64	2.33	2.38	2.62	ns
1.5 V LVC MOS	2 mA	2	High	5	–	1.55	2.92	0.26	1.22	1.10	2.96	2.60	2.40	2.56	ns
1.2 V LVC MOS	1 mA	1	High	5	–	1.55	3.59	0.26	1.53	1.10	3.47	3.06	2.51	2.49	ns
1.2 V LVC MOS Wide Range ³	100 μA	1	High	5	–	1.55	3.59	0.26	1.53	1.10	3.47	3.06	2.51	2.49	ns

Notes:

1. The minimum drive strength for any LVC MOS 1.2 V or LVC MOS 3.3 V software configuration when run in wide range is $\pm 100\ \mu\text{A}$. Drive strength displayed in the software is supported for normal range only. For a detailed I/V curve, refer to the IBIS models.
2. All LVC MOS 3.3 V software macros support LVC MOS 3.3 V wide range as specified in the JESD-8B specification.
3. All LVC MOS 1.2 V software macros support LVC MOS 1.2 V wide range as specified in the JESD8-12 specification
4. For specific junction temperature and voltage supply levels, refer to Table 2-6 on page 2-7 for derating values.

Table 2-135 • 1.2 V LVC MOS High Slew

Commercial-Case Conditions: $T_J = 70^\circ\text{C}$, Worst-Case VCC = 1.14 V, Worst-Case VCCI = 1.14 V
Applicable to Standard Banks

Drive Strength	Speed Grade	t_{DOUT}	t_{DP}	t_{DIN}	t_{PY}	t_{EOUT}	t_{ZL}	t_{ZH}	t_{LZ}	t_{HZ}	Units
1 mA	Std.	1.55	8.57	0.26	1.53	1.10	8.23	7.38	2.51	2.39	ns

Note: For specific junction temperature and voltage supply levels, refer to Table 2-7 on page 2-7 for derating values.

Table 2-136 • 1.2 V LVC MOS High Slew – Applies to 1.2 V DC Core Voltage

Commercial-Case Conditions: $T_J = 70^\circ\text{C}$, Worst-Case VCC = 1.14 V, Worst-Case VCCI = 1.14 V
Applicable to Standard Banks

Drive Strength	Speed Grade	t_{DOUT}	t_{DP}	t_{DIN}	t_{PY}	t_{EOUT}	t_{ZL}	t_{ZH}	t_{LZ}	t_{HZ}	Units
1 mA	Std.	1.55	3.59	0.26	1.53	1.10	3.47	3.06	2.51	2.49	ns

Notes:

1. Software default selection highlighted in gray.
2. For specific junction temperature and voltage supply levels, refer to Table 2-7 on page 2-7 for derating values.

1.2 V LVC MOS Wide Range

Table 2-137 • Minimum and Maximum DC Input and Output Levels for LVC MOS 1.2 V Wide Range
Applicable to Advanced I/O Banks

1.2 V LVC MOS Wide Range		VIL		VIH		VOL	VOH	IOL	IOH	IOSL	IOSH	IIL ²	IIH ³
Drive Strength	Equivalent Software Default Drive Strength Option ¹	Min. V	Max. V	Min. V	Max. V	Max. V	Min. V	mA	mA	Max. mA ⁴	Max. mA ⁴	μA^5	μA^5
100 μA	2 mA	-0.3	0.35 * VCCI	0.65 * VCCI	1.26	0.25 * VCCI	0.75 * VCCI	100	100	20	26	10	10

Notes:

1. The minimum drive strength for the default LVC MOS 1.2 V software configuration when run in wide range is $\pm 100 \mu\text{A}$. The drive strength displayed in software is supported in normal range only. For a detailed I/V curve, refer to the IBIS models.
2. IIL is the input leakage current per I/O pin over recommended operation conditions where $-0.3 \text{ V} < V_{IN} < V_{IL}$.
3. IIH is the input leakage current per I/O pin over recommended operating conditions $V_{IH} < V_{IN} < V_{CCI}$. Input current is larger when operating outside recommended ranges.
4. Currents are measured at 100°C junction temperature and maximum voltage.
5. Currents are measured at 85°C junction temperature.
6. Software default selection highlighted in gray.

Table 2-147 • Minimum and Maximum DC Input and Output Levels

DC Parameter	Description	Min.	Typ.	Max.	Units
VCCI	Supply Voltage	2.375	2.5	2.625	V
VOL	Output Low Voltage	0.9	1.075	1.25	V
VOH	Output High Voltage	1.25	1.425	1.6	V
IOL ¹	Output Lower Current	0.65	0.91	1.16	mA
IOH ¹	Output High Current	0.65	0.91	1.16	mA
VI	Input Voltage	0		2.925	V
IIH ²	Input High Leakage Current			10	μA
IIL ²	Input Low Leakage Current			10	μA
VODIFF	Differential Output Voltage	250	350	450	mV
VOCM	Output Common-Mode Voltage	1.125	1.25	1.375	V
VICM	Input Common-Mode Voltage	0.05	1.25	2.35	V
VIDIFF ⁴	Input Differential Voltage	100	350		mV

Notes:

1. IOL/IOH is defined by VODIFF/(resistor network)
2. Currents are measured at 85°C junction temperature.

Table 2-148 • AC Waveforms, Measuring Points, and Capacitive Loads

Input Low (V)	Input High (V)	Measuring Point* (V)
1.075	1.325	Cross point

Note: *Measuring point = Vtrip. See Table 2-29 on page 2-28 for a complete table of trip points.

Timing Characteristics

1.5 V DC Core Voltage

Table 2-149 • LVDS – Applies to 1.5 V DC Core Voltage

Commercial-Case Conditions: T_J = 70°C, Worst-Case VCC = 1.425 V, Worst-Case VCCI = 2.3 V
Applicable to Standard Banks

Speed Grade	t _{DOUT}	t _{DP}	t _{DIN}	t _{py}	Units
Std.	0.97	1.67	0.19	1.31	ns

Note: For specific junction temperature and voltage supply levels, refer to Table 2-6 on page 2-7 and Table 2-7 on page 2-7 for derating values.

1.2 V DC Core Voltage

Table 2-150 • LVDS – Applies to 1.5 V DC Core Voltage

Commercial-Case Conditions: T_J = 70°C, Worst-Case VCC = 1.14 V, Worst-Case VCCI = 2.3 V
Applicable to Standard Banks

Speed Grade	t _{DOUT}	t _{DP}	t _{DIN}	t _{py}	Units
Std.	1.55	2.19	0.25	1.52	ns

Note: For specific junction temperature and voltage supply levels, refer to Table 2-6 on page 2-7 and Table 2-7 on page 2-7 for derating values.

Table 2-156 • Parameter Definition and Measuring Nodes

Parameter Name	Parameter Definition	Measuring Nodes (from, to)*
t _{OCLKQ}	Clock-to-Q of the Output Data Register	HH, DOUT
t _{OSUD}	Data Setup Time for the Output Data Register	FF, HH
t _{OHD}	Data Hold Time for the Output Data Register	FF, HH
t _{OSUE}	Enable Setup Time for the Output Data Register	GG, HH
t _{OHE}	Enable Hold Time for the Output Data Register	GG, HH
t _{OCLR2Q}	Asynchronous Clear-to-Q of the Output Data Register	LL, DOUT
t _{OREMCLR}	Asynchronous Clear Removal Time for the Output Data Register	LL, HH
t _{ORECCLR}	Asynchronous Clear Recovery Time for the Output Data Register	LL, HH
t _{OCLKQ}	Clock-to-Q of the Output Enable Register	HH, EOUT
t _{OESUD}	Data Setup Time for the Output Enable Register	JJ, HH
t _{OEHD}	Data Hold Time for the Output Enable Register	JJ, HH
t _{OESUE}	Enable Setup Time for the Output Enable Register	KK, HH
t _{OEHE}	Enable Hold Time for the Output Enable Register	KK, HH
t _{OECLR2Q}	Asynchronous Clear-to-Q of the Output Enable Register	II, EOUT
t _{OEREMCLR}	Asynchronous Clear Removal Time for the Output Enable Register	II, HH
t _{OERECCLR}	Asynchronous Clear Recovery Time for the Output Enable Register	II, HH
t _{ICLKQ}	Clock-to-Q of the Input Data Register	AA, EE
t _{ISUD}	Data Setup Time for the Input Data Register	CC, AA
t _{IHD}	Data Hold Time for the Input Data Register	CC, AA
t _{ISUE}	Enable Setup Time for the Input Data Register	BB, AA
t _{IHE}	Enable Hold Time for the Input Data Register	BB, AA
t _{ICLR2Q}	Asynchronous Clear-to-Q of the Input Data Register	DD, EE
t _{IREMCLR}	Asynchronous Clear Removal Time for the Input Data Register	DD, AA
t _{IRECCLR}	Asynchronous Clear Recovery Time for the Input Data Register	DD, AA

Note: *See Figure 2-17 on page 2-86 for more information.

1.2 V DC Core Voltage

Table 2-172 • Register Delays
Commercial-Case Conditions: T_J = 70°C, Worst-Case VCC = 1.14 V

Parameter	Description	Std.	Units
t _{CLKQ}	Clock-to-Q of the Core Register	1.61	ns
t _{SUD}	Data Setup Time for the Core Register	1.17	ns
t _{HD}	Data Hold Time for the Core Register	0.00	ns
t _{SUE}	Enable Setup Time for the Core Register	1.29	ns
t _{HE}	Enable Hold Time for the Core Register	0.00	ns
t _{CLR2Q}	Asynchronous Clear-to-Q of the Core Register	0.87	ns
t _{PRE2Q}	Asynchronous Preset-to-Q of the Core Register	0.89	ns
t _{REMCLR}	Asynchronous Clear Removal Time for the Core Register	0.00	ns
t _{RECCLR}	Asynchronous Clear Recovery Time for the Core Register	0.24	ns
t _{REMPRE}	Asynchronous Preset Removal Time for the Core Register	0.00	ns
t _{RECPRE}	Asynchronous Preset Recovery Time for the Core Register	0.24	ns
t _{WCLR}	Asynchronous Clear Minimum Pulse Width for the Core Register	0.46	ns
t _{WPRE}	Asynchronous Preset Minimum Pulse Width for the Core Register	0.46	ns
t _{CKMPWH}	Clock Minimum Pulse Width High for the Core Register	0.95	ns
t _{CKMPWL}	Clock Minimum Pulse Width Low for the Core Register	0.95	ns

Note: For specific junction temperature and voltage supply levels, refer to Table 2-7 on page 2-7 for derating values.

Table 2-187 • AGL600 Global Resource
Commercial-Case Conditions: $T_J = 70^\circ\text{C}$, $V_{CC} = 1.14\text{ V}$

Parameter	Description	Std.		Units
		Min. ¹	Max. ²	
t _{RCKL}	Input Low Delay for Global Clock	2.22	2.67	ns
t _{RCKH}	Input High Delay for Global Clock	2.32	2.93	ns
t _{RCKMPWH}	Minimum Pulse Width High for Global Clock	1.40		ns
t _{RCKMPWL}	Minimum Pulse Width Low for Global Clock	1.65		ns
t _{RCKSW}	Maximum Skew for Global Clock		0.61	ns

Notes:

1. Value reflects minimum load. The delay is measured from the CCC output to the clock pin of a sequential element, located in a lightly loaded row (single element is connected to the global net).
2. Value reflects maximum load. The delay is measured on the clock pin of the farthest sequential element, located in a fully loaded row (all available flip-flops are connected to the global net in the row).
3. For specific junction temperature and voltage supply levels, refer to Table 2-6 on page 2-7 for derating values.

Table 2-188 • AGL1000 Global Resource
Commercial-Case Conditions: $T_J = 70^\circ\text{C}$, $V_{CC} = 1.14\text{ V}$

Parameter	Description	Std.		Units
		Min. ¹	Max. ²	
t _{RCKL}	Input Low Delay for Global Clock	2.31	2.76	ns
t _{RCKH}	Input High Delay for Global Clock	2.42	3.03	ns
t _{RCKMPWH}	Minimum Pulse Width High for Global Clock	1.40		ns
t _{RCKMPWL}	Minimum Pulse Width Low for Global Clock	1.65		ns
t _{RCKSW}	Maximum Skew for Global Clock		0.61	ns

Notes:

1. Value reflects minimum load. The delay is measured from the CCC output to the clock pin of a sequential element, located in a lightly loaded row (single element is connected to the global net).
2. Value reflects maximum load. The delay is measured on the clock pin of the farthest sequential element, located in a fully loaded row (all available flip-flops are connected to the global net in the row).
3. For specific junction temperature and voltage supply levels, refer to Table 2-6 on page 2-7 for derating values.

Timing Waveforms

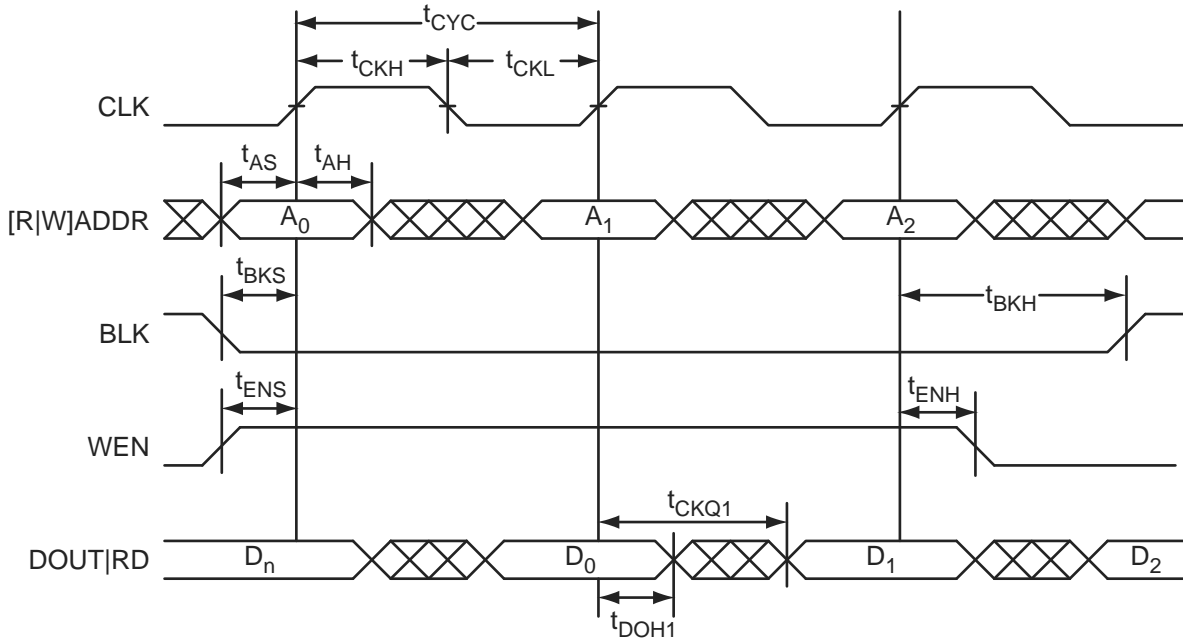


Figure 2-32 • RAM Read for Pass-Through Output. Applicable to Both RAM4K9 and RAM512x18.

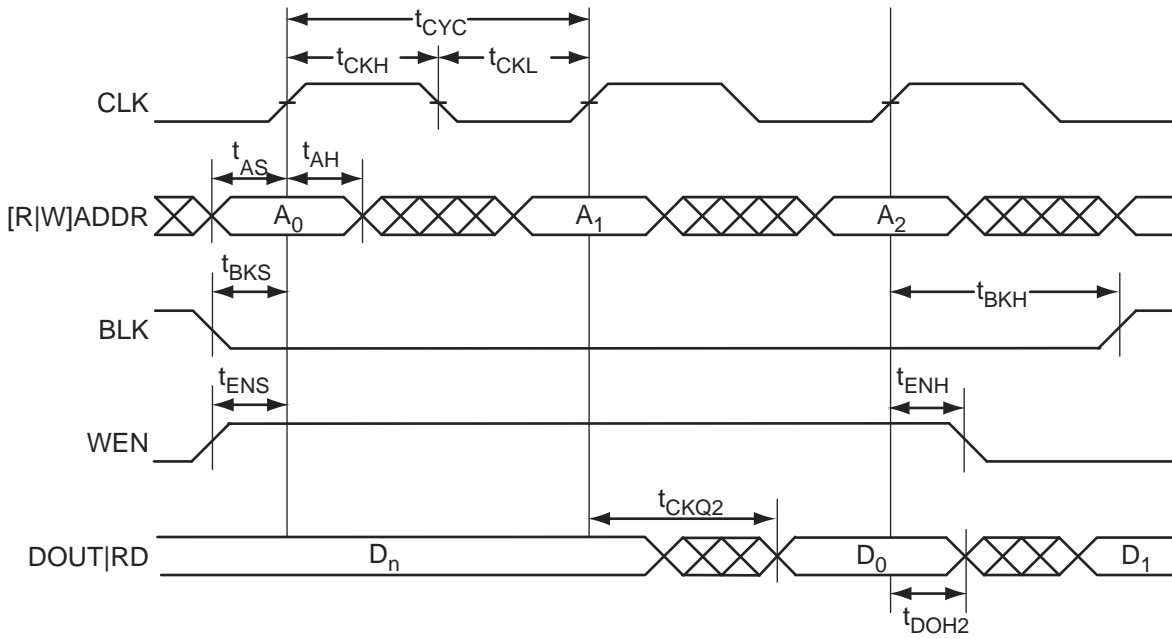


Figure 2-33 • RAM Read for Pipelined Output. Applicable to Both RAM4K9 and RAM512x18.

JTAG 1532 Characteristics

JTAG timing delays do not include JTAG I/Os. To obtain complete JTAG timing, add I/O buffer delays to the corresponding standard selected; refer to the I/O timing characteristics in the "User I/O Characteristics" section on page 2-20 for more details.

Timing Characteristics

Table 2-199 • JTAG 1532

Commercial-Case Conditions: T_J = 70°C, Worst-Case VCC = 1.425 V

Parameter	Description	Std.	Units
t _{DISU}	Test Data Input Setup Time	1.00	ns
t _{DIHD}	Test Data Input Hold Time	2.00	ns
t _{TMSSU}	Test Mode Select Setup Time	1.00	ns
t _{TMDHD}	Test Mode Select Hold Time	2.00	ns
t _{TCK2Q}	Clock to Q (data out)	8.00	ns
t _{RSTB2Q}	Reset to Q (data out)	25.00	ns
F _{TCKMAX}	TCK Maximum Frequency	15	MHz
t _{TRSTREM}	ResetB Removal Time	0.58	ns
t _{TRSTREC}	ResetB Recovery Time	0.00	ns
t _{TRSTMPW}	ResetB Minimum Pulse	TBD	ns

Note: For specific junction temperature and voltage supply levels, refer to Table 2-6 on page 2-7 for derating values.

Table 2-200 • JTAG 1532

Commercial-Case Conditions: T_J = 70°C, Worst-Case VCC = 1.14 V

Parameter	Description	Std.	Units
t _{DISU}	Test Data Input Setup Time	1.50	ns
t _{DIHD}	Test Data Input Hold Time	3.00	ns
t _{TMSSU}	Test Mode Select Setup Time	1.50	ns
t _{TMDHD}	Test Mode Select Hold Time	3.00	ns
t _{TCK2Q}	Clock to Q (data out)	11.00	ns
t _{RSTB2Q}	Reset to Q (data out)	30.00	ns
F _{TCKMAX}	TCK Maximum Frequency	9.00	MHz
t _{TRSTREM}	ResetB Removal Time	1.18	ns
t _{TRSTREC}	ResetB Recovery Time	0.00	ns
t _{TRSTMPW}	ResetB Minimum Pulse	TBD	ns

Note: For specific junction temperature and voltage supply levels, refer to Table 2-6 on page 2-7 for derating values.

The Flash*Freeze pin can be used with any single-ended I/O standard supported by the I/O bank in which the pin is located, and input signal levels compatible with the I/O standard selected. The FF pin should be treated as a sensitive asynchronous signal. When defining pin placement and board layout, simultaneously switching outputs (SSOs) and their effects on sensitive asynchronous pins must be considered.

Unused FF or I/O pins are tristated with weak pull-up. This default configuration applies to both Flash*Freeze mode and normal operation mode. No user intervention is required.

Table 3-1 shows the Flash*Freeze pin location on the available packages for IGLOO a devices. The Flash*Freeze pin location is independent of device, allowing migration to larger or smaller IGLOO devices while maintaining the same pin location on the board. Refer to the "Flash*Freeze Technology and Low Power Modes" chapter of the *IGLOO FPGA Fabric User Guide* for more information on I/O states during Flash*Freeze mode.

Table 3-1 • Flash*Freeze Pin Location in IGLOO Family Packages (device-independent)

IGLOO Packages	Flash*Freeze Pin
CS81/UC81	H2
CS121	J5
CS196	P3
CS281	W2
QN48	14
QN68	18
QN132	B12
VQ100	27
FG144	L3
FG256	T3
FG484	W6

QN132	
Pin Number	AGL125 Function
A1	GAB2/IO69RSB1
A2	IO130RSB1
A3	VCCIB1
A4	GFC1/IO126RSB1
A5	GFB0/IO123RSB1
A6	VCCPLF
A7	GFA1/IO121RSB1
A8	GFC2/IO118RSB1
A9	IO115RSB1
A10	VCC
A11	GEB1/IO110RSB1
A12	GEA0/IO107RSB1
A13	GEC2/IO104RSB1
A14	IO100RSB1
A15	VCC
A16	IO99RSB1
A17	IO96RSB1
A18	IO94RSB1
A19	IO91RSB1
A20	IO85RSB1
A21	IO79RSB1
A22	VCC
A23	GDB2/IO71RSB1
A24	TDI
A25	TRST
A26	GDC1/IO61RSB0
A27	VCC
A28	IO60RSB0
A29	GCC2/IO59RSB0
A30	GCA2/IO57RSB0
A31	GCA0/IO56RSB0
A32	GCB1/IO53RSB0
A33	IO49RSB0
A34	VCC
A35	IO44RSB0
A36	GBA2/IO41RSB0

QN132	
Pin Number	AGL125 Function
A37	GBB1/IO38RSB0
A38	GBC0/IO35RSB0
A39	VCCIB0
A40	IO28RSB0
A41	IO22RSB0
A42	IO18RSB0
A43	IO14RSB0
A44	IO11RSB0
A45	IO07RSB0
A46	VCC
A47	GAC1/IO05RSB0
A48	GAB0/IO02RSB0
B1	IO68RSB1
B2	GAC2/IO131RSB1
B3	GND
B4	GFC0/IO125RSB1
B5	VCOMPLF
B6	GND
B7	GFB2/IO119RSB1
B8	IO116RSB1
B9	GND
B10	GEB0/IO109RSB1
B11	VMV1
B12	FF/GEB2/IO105RSB1
B13	IO101RSB1
B14	GND
B15	IO98RSB1
B16	IO95RSB1
B17	GND
B18	IO87RSB1
B19	IO81RSB1
B20	GND
B21	GNDQ
B22	TMS
B23	TDO
B24	GDC0/IO62RSB0

QN132	
Pin Number	AGL125 Function
B25	GND
B26	NC
B27	GCB2/IO58RSB0
B28	GND
B29	GCB0/IO54RSB0
B30	GCC1/IO51RSB0
B31	GND
B32	GBB2/IO43RSB0
B33	VMV0
B34	GBA0/IO39RSB0
B35	GBC1/IO36RSB0
B36	GND
B37	IO26RSB0
B38	IO21RSB0
B39	GND
B40	IO13RSB0
B41	IO08RSB0
B42	GND
B43	GAC0/IO04RSB0
B44	GNDQ
C1	GAA2/IO67RSB1
C2	IO132RSB1
C3	VCC
C4	GFB1/IO124RSB1
C5	GFA0/IO122RSB1
C6	GFA2/IO120RSB1
C7	IO117RSB1
C8	VCCIB1
C9	GEA1/IO108RSB1
C10	GNDQ
C11	GEA2/IO106RSB1
C12	IO103RSB1
C13	VCCIB1
C14	IO97RSB1
C15	IO93RSB1
C16	IO89RSB1

VQ100	
Pin Number	AGL125 Function
1	GND
2	GAA2/IO67RSB1
3	IO68RSB1
4	GAB2/IO69RSB1
5	IO132RSB1
6	GAC2/IO131RSB1
7	IO130RSB1
8	IO129RSB1
9	GND
10	GFB1/IO124RSB1
11	GFB0/IO123RSB1
12	VCOMPLF
13	GFA0/IO122RSB1
14	VCCPLF
15	GFA1/IO121RSB1
16	GFA2/IO120RSB1
17	VCC
18	VCCIB1
19	GEC0/IO111RSB1
20	GEB1/IO110RSB1
21	GEB0/IO109RSB1
22	GEA1/IO108RSB1
23	GEA0/IO107RSB1
24	VMV1
25	GNDQ
26	GEA2/IO106RSB1
27	FF/GEB2/IO105RSB1
28	GEC2/IO104RSB1
29	IO102RSB1
30	IO100RSB1
31	IO99RSB1
32	IO97RSB1
33	IO96RSB1
34	IO95RSB1
35	IO94RSB1

VQ100	
Pin Number	AGL125 Function
36	IO93RSB1
37	VCC
38	GND
39	VCCIB1
40	IO87RSB1
41	IO84RSB1
42	IO81RSB1
43	IO75RSB1
44	GDC2/IO72RSB1
45	GDB2/IO71RSB1
46	GDA2/IO70RSB1
47	TCK
48	TDI
49	TMS
50	VMV1
51	GND
52	VPUMP
53	NC
54	TDO
55	TRST
56	VJTAG
57	GDA1/IO65RSB0
58	GDC0/IO62RSB0
59	GDC1/IO61RSB0
60	GCC2/IO59RSB0
61	GCB2/IO58RSB0
62	GCA0/IO56RSB0
63	GCA1/IO55RSB0
64	GCC0/IO52RSB0
65	GCC1/IO51RSB0
66	VCCIB0
67	GND
68	VCC
69	IO47RSB0
70	GBC2/IO45RSB0
71	GBB2/IO43RSB0

VQ100	
Pin Number	AGL125 Function
72	IO42RSB0
73	GBA2/IO41RSB0
74	VMV0
75	GNDQ
76	GBA1/IO40RSB0
77	GBA0/IO39RSB0
78	GBB1/IO38RSB0
79	GBB0/IO37RSB0
80	GBC1/IO36RSB0
81	GBC0/IO35RSB0
82	IO32RSB0
83	IO28RSB0
84	IO25RSB0
85	IO22RSB0
86	IO19RSB0
87	VCCIB0
88	GND
89	VCC
90	IO15RSB0
91	IO13RSB0
92	IO11RSB0
93	IO09RSB0
94	IO07RSB0
95	GAC1/IO05RSB0
96	GAC0/IO04RSB0
97	GAB1/IO03RSB0
98	GAB0/IO02RSB0
99	GAA1/IO01RSB0
100	GAA0/IO00RSB0

FG144	
Pin Number	AGL250 Function
K1	GEB0/IO99NDB3
K2	GEA1/IO98PDB3
K3	GEA0/IO98NDB3
K4	GEA2/IO97RSB2
K5	IO90RSB2
K6	IO84RSB2
K7	GND
K8	IO66RSB2
K9	GDC2/IO63RSB2
K10	GND
K11	GDA0/IO60VDB1
K12	GDB0/IO59VDB1
L1	GND
L2	VMV3
L3	FF/GEB2/IO96RSB2
L4	IO91RSB2
L5	VCCIB2
L6	IO82RSB2
L7	IO80RSB2
L8	IO72RSB2
L9	TMS
L10	VJTAG
L11	VMV2
L12	TRST
M1	GNDQ
M2	GEC2/IO95RSB2
M3	IO92RSB2
M4	IO89RSB2
M5	IO87RSB2
M6	IO85RSB2
M7	IO78RSB2
M8	IO76RSB2
M9	TDI
M10	VCCIB2
M11	VPUMP
M12	GNDQ

FG144	
Pin Number	AGL400 Function
A1	GNDQ
A2	VMV0
A3	GAB0/IO02RSB0
A4	GAB1/IO03RSB0
A5	IO16RSB0
A6	GND
A7	IO30RSB0
A8	VCC
A9	IO34RSB0
A10	GBA0/IO58RSB0
A11	GBA1/IO59RSB0
A12	GNDQ
B1	GAB2/IO154UDB3
B2	GND
B3	GAA0/IO00RSB0
B4	GAA1/IO01RSB0
B5	IO14RSB0
B6	IO19RSB0
B7	IO23RSB0
B8	IO31RSB0
B9	GBB0/IO56RSB0
B10	GBB1/IO57RSB0
B11	GND
B12	VMV1
C1	IO154VDB3
C2	GFA2/IO144PPB3
C3	GAC2/IO153UDB3
C4	VCC
C5	IO12RSB0
C6	IO17RSB0
C7	IO25RSB0
C8	IO32RSB0
C9	IO53RSB0
C10	GBA2/IO60PDB1
C11	IO60NDB1
C12	GBC2/IO62PPB1

FG144	
Pin Number	AGL400 Function
D1	IO149NDB3
D2	IO149PDB3
D3	IO153VDB3
D4	GAA2/IO155UPB3
D5	GAC0/IO04RSB0
D6	GAC1/IO05RSB0
D7	GBC0/IO54RSB0
D8	GBC1/IO55RSB0
D9	GBB2/IO61PDB1
D10	IO61NDB1
D11	IO62NPB1
D12	GCB1/IO68PPB1
E1	VCC
E2	GFC0/IO147NDB3
E3	GFC1/IO147PDB3
E4	VCCIB3
E5	IO155VPB3
E6	VCCIB0
E7	VCCIB0
E8	GCC1/IO67PDB1
E9	VCCIB1
E10	VCC
E11	GCA0/IO69NDB1
E12	IO70NDB1
F1	GFB0/IO146NPB3
F2	VCOMPLF
F3	GFB1/IO146PPB3
F4	IO144NPB3
F5	GND
F6	GND
F7	GND
F8	GCC0/IO67NDB1
F9	GCB0/IO68NPB1
F10	GND
F11	GCA1/IO69PDB1
F12	GCA2/IO70PDB1

FG144	
Pin Number	AGL400 Function
G1	GFA1/IO145PPB3
G2	GND
G3	VCCPLF
G4	GFA0/IO145NPB3
G5	GND
G6	GND
G7	GND
G8	GDC1/IO77UPB1
G9	IO72NDB1
G10	GCC2/IO72PDB1
G11	IO71NDB1
G12	GCB2/IO71PDB1
H1	VCC
H2	GFB2/IO143PDB3
H3	GFC2/IO142PSB3
H4	GEC1/IO137PDB3
H5	VCC
H6	IO75PDB1
H7	IO75NDB1
H8	GDB2/IO81RSB2
H9	GDC0/IO77VPB1
H10	VCCIB1
H11	IO73PSB1
H12	VCC
J1	GEB1/IO136PDB3
J2	IO143NDB3
J3	VCCIB3
J4	GEC0/IO137NDB3
J5	IO125RSB2
J6	IO116RSB2
J7	VCC
J8	TCK
J9	GDA2/IO80RSB2
J10	TDO
J11	GDA1/IO79UDB1
J12	GDB1/IO78UDB1

FG144	
Pin Number	AGL400 Function
K1	GEB0/IO136NDB3
K2	GEA1/IO135PDB3
K3	GEA0/IO135NDB3
K4	GEA2/IO134RSB2
K5	IO127RSB2
K6	IO121RSB2
K7	GND
K8	IO104RSB2
K9	GDC2/IO82RSB2
K10	GND
K11	GDA0/IO79VDB1
K12	GDB0/IO78VDB1
L1	GND
L2	VMV3
L3	FF/GEB2/IO133RSB2
L4	IO128RSB2
L5	VCCIB2
L6	IO119RSB2
L7	IO114RSB2
L8	IO110RSB2
L9	TMS
L10	VJTAG
L11	VMV2
L12	TRST
M1	GNDQ
M2	GEC2/IO132RSB2
M3	IO129RSB2
M4	IO126RSB2
M5	IO124RSB2
M6	IO122RSB2
M7	IO117RSB2
M8	IO115RSB2
M9	TDI
M10	VCCIB2
M11	VPUMP
M12	GNDQ

FG484	
Pin Number	AGL400 Function
B7	NC
B8	NC
B9	NC
B10	NC
B11	NC
B12	NC
B13	NC
B14	NC
B15	NC
B16	NC
B17	NC
B18	NC
B19	NC
B20	NC
B21	VCCIB1
B22	GND
C1	VCCIB3
C2	NC
C3	NC
C4	NC
C5	GND
C6	NC
C7	NC
C8	VCC
C9	VCC
C10	NC
C11	NC
C12	NC
C13	NC
C14	VCC
C15	VCC
C16	NC
C17	NC
C18	GND
C19	NC
C20	NC

Package Pin Assignments

FG484	
Pin Number	AGL600 Function
E13	IO38RSB0
E14	IO42RSB0
E15	GBC1/IO55RSB0
E16	GBB0/IO56RSB0
E17	IO52RSB0
E18	GBA2/IO60PDB1
E19	IO60NDB1
E20	GND
E21	NC
E22	NC
F1	NC
F2	NC
F3	NC
F4	IO173NDB3
F5	IO174NDB3
F6	VMV3
F7	IO07RSB0
F8	GAC0/IO04RSB0
F9	GAC1/IO05RSB0
F10	IO20RSB0
F11	IO24RSB0
F12	IO33RSB0
F13	IO39RSB0
F14	IO44RSB0
F15	GBC0/IO54RSB0
F16	IO51RSB0
F17	VMV0
F18	IO61NPB1
F19	IO63PDB1
F20	NC
F21	NC
F22	NC
G1	IO170NDB3
G2	IO170PDB3
G3	NC
G4	IO171NDB3

FG484	
Pin Number	AGL1000 Function
C21	NC
C22	VCCIB1
D1	IO219PDB3
D2	IO220NDB3
D3	NC
D4	GND
D5	GAA0/IO00RSB0
D6	GAA1/IO01RSB0
D7	GAB0/IO02RSB0
D8	IO16RSB0
D9	IO22RSB0
D10	IO28RSB0
D11	IO35RSB0
D12	IO45RSB0
D13	IO50RSB0
D14	IO55RSB0
D15	IO61RSB0
D16	GBB1/IO75RSB0
D17	GBA0/IO76RSB0
D18	GBA1/IO77RSB0
D19	GND
D20	NC
D21	NC
D22	NC
E1	IO219NDB3
E2	NC
E3	GND
E4	GAB2/IO224PDB3
E5	GAA2/IO225PDB3
E6	GNDQ
E7	GAB1/IO03RSB0
E8	IO17RSB0
E9	IO21RSB0
E10	IO27RSB0
E11	IO34RSB0
E12	IO44RSB0

Revision	Changes	Page
Revision 19	<p>The following figures were deleted (SAR 29991). Reference was made to a new application note, <i>Simultaneous Read-Write Operations in Dual-Port SRAM for Flash-Based cSoCs and FPGAs</i>, which covers these cases in detail (SAR 21770).</p> <p>Figure 2-36 • Write Access after Write onto Same Address Figure 2-37 • Read Access after Write onto Same Address Figure 2-38 • Write Access after Read onto Same Address</p> <p>The port names in the SRAM "Timing Waveforms", SRAM "Timing Characteristics" tables, Figure 2-40 • FIFO Reset, and the FIFO "Timing Characteristics" tables were revised to ensure consistency with the software names (SARs 29991, 30510).</p> <p>The "Pin Descriptions" chapter has been added (SAR 21642).</p> <p>Package names used in the "Package Pin Assignments" section were revised to match standards given in <i>Package Mechanical Drawings</i> (SAR 27395).</p> <p>The "CS81" pin table for AGL250 is new (SAR 22737).</p> <p>The CS121 pin table for AGL125 is new (SAR 22737).</p> <p>The P3 function was revised in the "CS196" pin table for AGL250 (SAR 24800).</p> <p>The "QN132" pin table for AGL250 was added. The "FG144" pin table for AGL060 was added (SAR 33689)</p>	<p>N/A</p> <p>2-119 to 2-130</p> <p>3-1</p> <p>4-1</p> <p>4-5</p> <p>4-12</p> <p>4-35, 4-42</p>
July 2010	<p>The versioning system for datasheets has been changed. Datasheets are assigned a revision number that increments each time the datasheet is revised. The "IGLOO Device Status" table indicates the status for each device in the device family.</p>	N/A